

<b>Notice of References Cited</b>	Application/Control No. 10/040,759		Applicant(s)/Patent Under Reexamination KWON, HYUCK JIN	
	Examiner Khawar Iqbal		Art Unit 2617	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,865,261 B1	03-2005	Rao et al.	379/93.12
*	B	US-6,716,101 B1	04-2004	Meadows et al.	455/456.1
*	C	US-2005/0048978 A1	03-2005	Santhoff et al.	455/442
*	D	US-6,950,881 B1	09-2005	Ndili, Awele	709/246
*	E	US-2002/0046035 A1	04-2002	Kitahara et al.	704/277
*	F	US-7,031,703 B1	04-2006	Graf et al.	455/432.1
*	G	US-2002/0078092 A1	06-2002	Kim, Minhoe	707/513
*	H	US-2001/0012992	08-2001	Kimpara et al.	704/5
*	I	US-6,425,524 B2	07-2002	Pentel, Randolph M.	235/381
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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